

Contents

Preface to the Second Edition	xi
Preface to the First Edition	xiii
1 The Concept of Microstructure	1
1.1 Microstructural Features	7
1.1.1 Structure–Property Relationships	7
1.1.2 Microstructural Scale	10
1.1.3 Microstructural Parameters	19
1.2 Crystallography and Crystal Structure	24
1.2.1 Interatomic Bonding in Solids	25
1.2.2 Crystalline and Amorphous Phases	30
1.2.3 The Crystal Lattice	30
Summary	42
Bibliography	46
Worked Examples	46
Problems	51
2 Diffraction Analysis of Crystal Structure	55
2.1 Scattering of Radiation by Crystals	56
2.1.1 The Laue Equations and Bragg’s Law	56
2.1.2 Allowed and Forbidden Reflections	59
2.2 Reciprocal Space	60
2.2.1 The Limiting Sphere Construction	60
2.2.2 Vector Representation of Bragg’s Law	61
2.2.3 The Reciprocal Lattice	61
2.3 X-Ray Diffraction Methods	63
2.3.1 The X-Ray Diffractometer	67
2.3.2 Powder Diffraction–Particles and Polycrystals	73
2.3.3 Single Crystal Laue Diffraction	76
2.3.4 Rotating Single Crystal Methods	78
2.4 Diffraction Analysis	79
2.4.1 Atomic Scattering Factors	80
2.4.2 Scattering by the Unit Cell	81
2.4.3 The Structure Factor in the Complex Plane	83
2.4.4 Interpretation of Diffracted Intensities	84
2.4.5 Errors and Assumptions	85
2.5 Electron Diffraction	90
2.5.1 Wave Properties of Electrons	91

2.5.2	Ring Patterns, Spot Patterns and Laue Zones	94
2.5.3	Kikuchi Patterns and Their Interpretation	96
	Summary	98
	Bibliography	103
	Worked Examples	103
	Problems	114
3	Optical Microscopy	123
3.1	Geometrical Optics	125
3.1.1	Optical Image Formation	125
3.1.2	Resolution in the Optical Microscope	130
3.1.3	Depth of Field and Depth of Focus	133
3.2	Construction of The Microscope	134
3.2.1	Light Sources and Condenser Systems	134
3.2.2	The Specimen Stage	136
3.2.3	Selection of Objective Lenses	136
3.2.4	Image Observation and Recording	139
3.3	Specimen Preparation	143
3.3.1	Sampling and Sectioning	143
3.3.2	Mounting and Grinding	144
3.3.3	Polishing and Etching Methods	145
3.4	Image Contrast	148
3.4.1	Reflection and Absorption of Light	149
3.4.2	Bright-Field and Dark-Field Image Contrast	150
3.4.3	Confocal Microscopy	152
3.4.4	Interference Contrast and Interference Microscopy	152
3.4.5	Optical Anisotropy and Polarized Light	157
3.4.6	Phase Contrast Microscopy	163
3.5	Working with Digital Images	165
3.5.1	Data Collection and The Optical System	165
3.5.2	Data Processing and Analysis	165
3.5.3	Data Storage and Presentation	166
3.5.4	Dynamic Range and Digital Storage	167
3.6	Resolution, Contrast and Image Interpretation	170
	Summary	171
	Bibliography	173
	Worked Examples	173
	Problems	176
4	Transmission Electron Microscopy	179
4.1	Basic Principles	185
4.1.1	Wave Properties of Electrons	185
4.1.2	Resolution Limitations and Lens Aberrations	187
4.1.3	Comparative Performance of Transmission and Scanning Electron Microscopy	192

4.2	Specimen Preparation	194
4.2.1	Mechanical Thinning	195
4.2.2	Electrochemical Thinning	198
4.2.3	Ion Milling	199
4.2.4	Sputter Coating and Carbon Coating	201
4.2.5	Replica Methods	202
4.3	The Origin of Contrast	203
4.3.1	Mass–Thickness Contrast	205
4.3.2	Diffraction Contrast and Crystal Lattice Defects	205
4.3.3	Phase Contrast and Lattice Imaging	207
4.4	Kinematic Interpretation of Diffraction Contrast	213
4.4.1	Kinematic Theory of Electron Diffraction	213
4.4.2	The Amplitude–Phase Diagram	213
4.4.3	Contrast From Lattice Defects	215
4.4.4	Stacking Faults and Anti-Phase Boundaries	216
4.4.5	Edge and Screw Dislocations	218
4.4.6	Point Dilatations and Coherency Strains	219
4.5	Dynamic Diffraction and Absorption Effects	221
4.5.1	Stacking Faults Revisited	227
4.5.2	Quantitative Analysis of Contrast	230
4.6	Lattice Imaging at High Resolution	230
4.6.1	The Lattice Image and the Contrast Transfer Function	230
4.6.2	Computer Simulation of Lattice Images	231
4.6.3	Lattice Image Interpretation	232
4.7	Scanning Transmission Electron Microscopy	234
	Summary	236
	Bibliography	238
	Worked Examples	238
	Problems	247
5	Scanning Electron Microscopy	261
5.1	Components of The Scanning Electron Microscope	262
5.2	Electron Beam–Specimen Interactions	264
5.2.1	Beam-Focusing Conditions	265
5.2.2	Inelastic Scattering and Energy Losses	266
5.3	Electron Excitation of X-Rays	269
5.3.1	Characteristic X-Ray Images	271
5.4	Backscattered Electrons	277
5.4.1	Image Contrast in Backscattered Electron Images	279
5.5	Secondary Electron Emission	280
5.5.1	Factors Affecting Secondary Electron Emission	283
5.5.2	Secondary Electron Image Contrast	286
5.6	Alternative Imaging Modes	288
5.6.1	Cathodoluminescence	288
5.6.2	Electron Beam Induced Current	288
5.6.3	Orientation Imaging Microscopy	289

5.6.4	Electron Backscattered Diffraction Patterns	289
5.6.5	OIM Resolution and Sensitivity	291
5.6.6	Localized Preferred Orientation and Residual Stress	292
5.7	Specimen Preparation and Topology	294
5.7.1	Sputter Coating and Contrast Enhancement	295
5.7.2	Fractography and Failure Analysis	295
5.7.3	Stereoscopic Imaging	298
5.7.4	Parallax Measurements	298
5.8	Focused Ion Beam Microscopy	301
5.8.1	Principles of Operation and Microscope Construction	302
5.8.2	Ion Beam–Specimen Interactions	304
5.8.3	Dual-Beam FIB Systems	306
5.8.4	Machining and Deposition	306
5.8.5	TEM Specimen Preparation	310
5.8.6	Serial Sectioning	314
	Summary	315
	Bibliography	318
	Worked Examples	318
	Problems	326
6	Microanalysis in Electron Microscopy	333
6.1	X-Ray Microanalysis	334
6.1.1	Excitation of Characteristic X-Rays	334
6.1.2	Detection of Characteristic X-Rays	338
6.1.3	Quantitative Analysis of Composition	343
6.2	Electron Energy Loss Spectroscopy	357
6.2.1	The Electron Energy-Loss Spectrum	360
6.2.2	Limits of Detection and Resolution in EELS	361
6.2.3	Quantitative Electron Energy Loss Analysis	364
6.2.4	Near-Edge Fine Structure Information	365
6.2.5	Far-Edge Fine Structure Information	366
6.2.6	Energy-Filtered Transmission Electron Microscopy	367
	Summary	370
	Bibliography	375
	Worked Examples	375
	Problems	386
7	Scanning Probe Microscopy and Related Techniques	391
7.1	Surface Forces and Surface Morphology	392
7.1.1	Surface Forces and Their Origin	392
7.1.2	Surface Force Measurements	396
7.1.3	Surface Morphology: Atomic and Lattice Resolution	397
7.2	Scanning Probe Microscopes	400
7.2.1	Atomic Force Microscopy	403
7.2.2	Scanning Tunnelling Microscopy	410
7.3	Field-Ion Microscopy and Atom Probe Tomography	413

7.3.1	Identifying Atoms by Field Evaporation	414
7.3.2	The Atom Probe and Atom Probe Tomography	416
	Summary	417
	Bibliography	420
	Problems	420
8	Chemical Analysis of Surface Composition	423
8.1	X-Ray Photoelectron Spectroscopy	424
8.1.1	Depth Discrimination	426
8.1.2	Chemical Binding States	428
8.1.3	Instrumental Requirements	429
8.1.4	Applications	431
8.2	Auger Electron Spectroscopy	431
8.2.1	Spatial Resolution and Depth Discrimination	433
8.2.2	Recording and Presentation of Spectra	434
8.2.3	Identification of Chemical Binding States	435
8.2.4	Quantitative Auger Analysis	436
8.2.5	Depth Profiling	437
8.2.6	Auger Imaging	438
8.3	Secondary-Ion Mass Spectrometry	440
8.3.1	Sensitivity and Resolution	442
8.3.2	Calibration and Quantitative Analysis	444
8.3.3	SIMS Imaging	445
	Summary	446
	Bibliography	448
	Worked Examples	448
	Problems	453
9	Quantitative and Tomographic Analysis of Microstructure	457
9.1	Basic Stereological Concepts	458
9.1.1	Isotropy and Anisotropy	459
9.1.2	Homogeneity and Inhomogeneity	461
9.1.3	Sampling and Sectioning	463
9.1.4	Statistics and Probability	466
9.2	Accessible and Inaccessible Parameters	467
9.2.1	Accessible Parameters	468
9.2.2	Inaccessible Parameters	476
9.3	Optimizing Accuracy	481
9.3.1	Sample Size and Counting Time	483
9.3.2	Resolution and Detection Errors	485
9.3.3	Sample Thickness Corrections	487
9.3.4	Observer Bias	489
9.3.5	Dislocation Density Revisited	490
9.4	Automated Image Analysis	491
9.4.1	Digital Image Recording	494
9.4.2	Statistical Significance and Microstructural Relevance	495

9.5	Tomography and Three-Dimensional Reconstruction	495
9.5.1	Presentation of Tomographic Data	496
9.5.2	Methods of Serial Sectioning	498
9.5.3	Three-Dimensional Reconstruction	499
	Summary	500
	Bibliography	503
	Worked Examples	503
	Problems	514
Appendices		517
	Appendix 1: Useful Equations	517
	Interplanar Spacings	517
	Unit Cell Volumes	518
	Interplanar Angles	518
	Direction Perpendicular to a Crystal Plane	519
	Hexagonal Unit Cells	520
	The Zone Axis of Two Planes in the Hexagonal System	521
	Appendix 2: Wavelengths	521
	Relativistic Electron Wavelengths	521
	X-Ray Wavelengths for Typical X-Ray Sources	521
	Index	523